

Additively Manufactured Plastic Plasma Spectrometer

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Abstract

We report results in development and testing of a low resource top hat electrostatic analyzer (ESA) for space plasma measurements. This device has been additively manufactured (3D-printed) using fused deposition modeling. The classic top hat design is composed of four plastic pieces, without any surface coatings. The three conducting electrodes are printed from carbon nanotube infused polyether ether ketone (CNT-PEEK). The fourth piece, an insulating electrode support, uses pure PEEK. This ESA is designed to detect electrons in space from 10eV up to 30 keV. We demonstrate that the printed CNT-PEEK is sufficiently electrically conductive to support the fast high voltage slewing often required for high time resolution measurements. The plastic ESA has been successfully vibrated beyond standard pre-flight levels, tested under keV electron beam illumination over a wide range of temperatures, and tested under UV illumination, simulating the solar Ly- α flux. In comparison with an identical machined aluminum ESA, our CNT-PEEK ESA provides nominal energy/angle band passes, closely matching simulation. These band passes imply minimal impact from surface charging at beam energies of 2-3 keV, although more investigation is needed. We also find that the CNT-PEEK ESA provides far superior out-of-band electron rejection and UV photon rejection compared to the machined aluminum ESA. We do not detect any problems with trapped gases or outgassing. This development offers potential for significant mass savings, implementation of otherwise unattainable geometric configurations, and dramatic simplification in manufacturing and assembly processes required for development of space plasma instruments.

1. Introduction

Electrostatic Analyzers (ESAs) are common in Heliophysics missions and on Planetary missions that feature an in-situ space plasma component. In situ sampling of the local environment, including electromagnetic fields, plasmas, and energetic particles, is essential for many NASA Heliophysics missions (National Research Council, 2013). An ESA is typically used in combination with electron multiplier particle detectors (Goodrich Wiley, 1979) to measure local plasma fluxes in 3D energy/angle space. While an ESA selects for energy-per-charge and at least one dimension of angle, the particle speed is unknown without also measuring the particle's mass-per-charge (m/q), which is sometimes included in a time-of-flight (Möbius, et al., 2016) or magnetic (Hoffman, et al., 1973) analyzer stage downstream of the ESA. However, in many space plasma applications, the charge state can be assumed to be ± 1 (electron or singly ionized ion) and the mass can be assumed to be that of the electron for negatively charged particles or of the proton for positively charged particles (e.g., protons are known to comprise 96% of the ion particle density in the solar wind (Robbins, et al., 1970)). If the particle m/q is measured or can be assumed, the ESA provides measurement of the single particle distribution function ($f(\mathbf{v})$), which satisfies Boltzmann's Equation, and its velocity-space integral moments. These comprise the key fluid state variables of the plasma, enabling meaningful scientific studies of the

plasma physics in process both at the site of the measurement and remotely from it.

In space flight, the size, weight, and power (SWaP) resources available to any instrument (like an ESA-based plasma instrument) are highly prized and limited. Therefore, strong motivation continually exists to minimize SWaP requirements. The recent proliferation of small spacecraft such as CubeSats has driven innovation in instrument design. We are motivated to make plasma instruments which are potentially viable on spacecraft as small as a 1-Unit CubeSat, which is a 10-cm cube about 1-2kg, and consuming about 1-2 W (Johnstone, 2020). The prospect of flying constellations of such small spacecraft for targeted scientific purposes further motivates reductions both in instrument SWaP requirements and in developmental complexity.

ESAs are traditionally fabricated from Aluminum using conventional machining, otherwise known as subtractive manufacturing (SM). We are exploring the use of Additive Manufacturing (AM), popularly referred to as 3D printing, for space flight instrument fabrication, beginning with design and AM-fabrication of ESAs. Use of AM rather than SM holds the potential to simplify instrument development and reduce instrument SWaP requirements via design elements not available using SM techniques. AM may enable the manufacture of a "monolithic" ESA; one solid part with no internal fasteners required. This approach will reduce variability in the manufacturing and assembly process and greatly simplify the development

1 process by eliminating interfaces between parts of the
 2 ESA. Finally, use of AM with appropriately selected
 3 materials may offer both enhanced electro-optical
 4 performance and functional design elements not practical
 5 to fabricate in the SM environment. AM can be performed
 6 with metals, plastics, or even ceramics, but this work is
 7 concerned only with plastics.

8 Here, we focus on the “tophat” ESA (Carlson et al., 1983;
 9 hereafter denoted C83), a popular ESA configuration (e.g.,
 10 Johnstone et al., 1997; Reme et al., 1997; Young et al.,
 11 2004; McFadden et al., 2009; Pollock et al., 2016;
 12 McComas et al., 2017) that we illustrate in Figure 1. The
 13 “tophat” nomenclature is somewhat colloquial in the
 14 broader scientific community and we differentiate between
 15 a tophat, which is a type of entire ESA, and a “top cap”,
 16 which is one of a tophat’s three electrodes, as is described
 17 subsequently. We have designed a tophat ESA whose size
 18 and shape can be accommodated by a standardized
 19 protrusion from a CubeSat within the “tuna can”, a
 20 cylindrical volume of 6.4 cm diameter x 3.6 cm length.
 21 This volume is normally unused and lies within the interior
 22 of the coil spring used to eject a CubeSat from its host
 23 deployer. Alternatively, this ESA’s cylindrical shape is
 24 also designed to fit within an ejectable sub-payload for a
 25 sounding rocket.

26 The main unusual feature of this ESA is that it is fully
 27 fabricated from Polyether ether ketone (PEEK). PEEK is a
 28 high-grade engineering plastic often used in electrically

32 surfaces must be avoided. The exclusive use of plastics for
 33 ESA fabrication is new, although plastics with coatings
 34 have been used in space before (Fedorov et al., 2011).
 35 Normally, metals such as aluminum are required for the
 36 conducting electrodes and grounded chassis elements in an
 37 ESA, to impose electric fields and to drain deposited
 38 charge away. New CNT-infused high temperature
 39 engineering plastics like PEEK (Mohiuddin and Van
 40 Hoa,2011) have useful electrical conductivity, enabling
 41 exploration of their use as electrodes in plasma
 42 instruments. The additional development of AM printers
 43 able to print high-temperature engineering plastics (Das, et
 44 al., 2020) enables the fabrication of complete ESAs from a
 45 combination of insulating and conductive PEEK. The
 46 conductivity of CNT-PEEK is low compared to metals, but
 47 still sufficient for draining away charge. While a metal
 48 might have a resistivity of $\sim 10^{-6} \Omega\text{-cm}$, CNT-PEEK can be
 49 in the range $\sim 10^{+1} \Omega\text{-cm}$ (Goncalves 2018), and can have a
 50 discharging time constant on the order of a microsecond
 51 based on our analysis.

52 The rest of this paper is organized as follows. In Section 2
 53 we describe more detail about ESAs and specifically the
 54 simulated parameters of our CNT-PEEK ESA. In Section
 55 3, we describe the AM fabrication process and some
 56 lessons that we have learned along the way. In Section 4,
 57 we describe performance testing under both electron
 58 beam and UV photon illumination in high vacuum, and
 59 summarize environmental testing that has been
 60 performed. In Section 5, we present our conclusions,

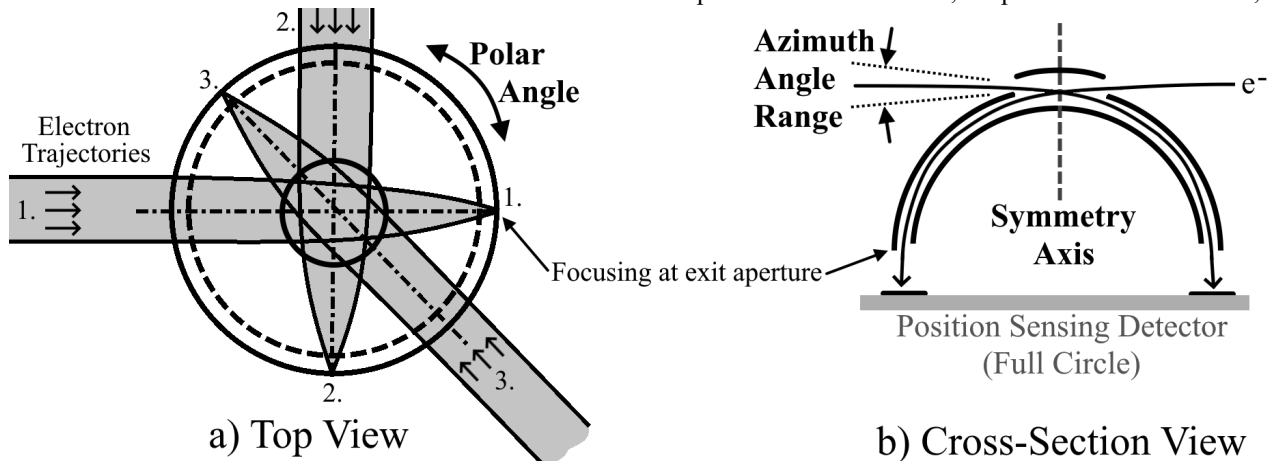


Figure 1: Top hat ESA conceptual diagrams: Top view (left) and cross section (right). Azimuth and polar angles referred to in text are indicated. (Reproduced from “An instrument for rapidly measuring plasma distribution functions with high resolution” by C.W. Carlson et al. *Advances in Space Research*. Vol.2 67-70 (1983) with permission from Elsevier.)

29 insulating components in space flight applications,
 30 particularly in high voltage applications and those where
 31 molecular contamination of sensitive optical and detection

61 address some pitfalls that may present themselves, and
 62 briefly discuss future developmental directions.

1

2 2. Design of the ESA

3 An ESA is composed of a pair of concentric curved
 4 conducting electrodes that are electrically biased with
 5 respect to one another so that a near-uniform electric field
 6 points from one plate to the other across the narrow, curved
 7 gap between them (See Figure 2). ESAs are deployed with
 8 one end of the curved gap (the entrance aperture) viewing
 9 the plasma and the other end (the exit aperture) facing a
 10 particle detector. A particle that enters the gap between the
 11 electrodes is deflected by the applied electric field. If the
 12 particles' kinetic energy/charge (E/q) is such that the
 13 electric field force is nearly equal to the centripetal force
 14 required to keep the particle on a circular trajectory
 15 between the plates, then it will impact the particle detector
 16 and be counted. If the particle's E/q is significantly higher
 17 or lower, it will impact the electrodes and be absorbed
 18 before it can reach the detector.

19 The "top hat" configuration shown in Figure 1 or some
 20 variation of it has become nearly ubiquitous in scientific
 21 in-situ space plasma measurements for particle energies of
 22 < 1 eV up to tens of keV. The C83 tophat ESA features two
 23 concentric and nearly hemispheric electrodes: the inner
 24 electrode and the center electrode. A grounded outer
 25 electrode, often referred to as the top cap, is added above
 26 the entrance aperture in the center electrode to contain the
 27 applied electric field and guide arriving particles into the
 28 curved gap. Charged particles within a narrow range of
 29 energy-per-charge (E/q) and azimuth angle freely fly

30 through the gap between the inner and center electrodes
 31 and emerge at an annular exit aperture near the hemispheric
 32 ESA's equatorial plane. This is illustrated in the simulation
 33 results shown in C83's Figure 3, as well as this paper's
 34 Figure 4. The center of the E/q band pass is directly
 35 proportional to the voltage applied to the inner electrode.
 36 The constant of proportionality, often referred to as the
 37 analyzer ratio or k-factor depends nearly exclusively on the
 38 ratio of the gap (Δ_1) between the inner and center electrodes
 39 to the radius (R_1) of the inner electrode. The inner electrode
 40 is biased with positive voltage to attract negatively charged
 41 particles (e.g., electrons), or negative for positively
 42 charged particles (e.g., protons). The center electrode and
 43 top cap are both typically grounded. The tophat ESA
 44 admits particles within a cylindrically radial field-of-view
 45 near a plane parallel to its equatorial plane and directs those
 46 that are transmitted to an annular detector area, typically
 47 the outer portion of a circular microchannel plate (MCP)
 48 detector. Particle detection implies the particle's E/q , given
 49 knowledge of the voltage applied to the inner electrode at
 50 the time of detection. 1-dimensional position sensing
 51 around the annular detector's circumference determines the
 52 particle's arriving polar angle (see Figure 1). Thus, with a
 53 single applied voltage and a fixed ESA orientation in space,
 54 the flux of particles arriving near a single E/q and azimuth
 55 angle (see Figure 1) can be measured as a function of polar
 56 angle. Controlled sweeping of the applied ESA voltage
 57 provides sequential sampling of multiple E/q values,
 58 admitting measurement of a 2D (E/q , polar angle) particle
 59 count spectrum near a fixed azimuth angle. Measurement

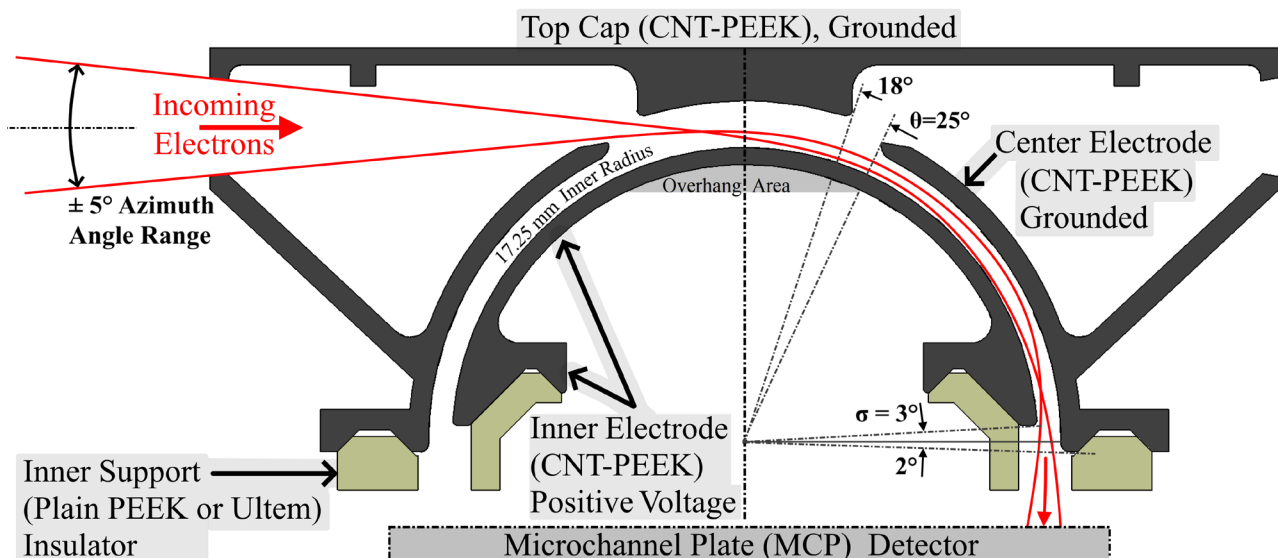


Figure 2: CNT-PEEK ESA section view from Solidworks® CAD showing the four main pieces and conceptual electron trajectories

1 of the full 3D velocity space is most commonly achieved
2 by mounting a top hat ESA on a spinning spacecraft as in
3 the Hot Plasma Composition Spectrometer (Young et al.,
4 2016) on NASA’s Magnetospheric Multiscale (MMS;
5 Burch et al., 2016). Alternatively, pitch angle
6 measurements can be obtained without spinning, if the
7 spacecraft remains oriented so that the magnetic field
8 vector is perpendicular to the ESA’s symmetry axis. More
9 rapid 3D velocity space measurements were enabled in the
10 case of the MMS Fast Plasma Investigation (FPI; Pollock
11 et al., 2016) by placing a large number (8 for electrons and
12 8 for ions) of top hat ESAs each viewing different planes
13 in velocity space. More rapid or comprehensive
14 measurements can also be made by mechanically or
15 electrostatically scanning the field of view, or with a design
16 of ESA that captures a wider field of view instantaneously,
17 such as FIPS on the MESSENGER spacecraft (Andrews
18 et al, 2007), or the designs in (Vaisberg et al, 2001) and
19 (Morel et al, 2017).

20 The ESA was designed based on the study of C83 and is
21 optimized for measuring auroral electrons in the E/q range
22 between 10 eV and 30 keV. Figure 2 shows a cross section
23 of the design, which was modeled in SolidWorks and
24 optimized based on SIMION™ electron ray tracing.
25 Critical design parameter selections as defined by C83 are
26 listed in Table 1.

27 We attempted to design an ESA with relatively generic
28 design parameters to be relevant for most science
29 applications. The ratio Δ_1/R_1 controls the top hat ESA
30 performance and, along with the radius of the ESA, its
31 sensitivity as described in C83. For a fixed Δ_1/R_1 , the
32 instrument sensitivity scales with R_1^2 (a larger instrument
33 yields more collection area at the entrance aperture). For
34 fixed R_1 , the entrance aperture and both the energy and
35 azimuth angle band passes expand with increasing Δ_1 ,
36 yielding greater sensitivity. This comes at the expense of
37 both reduced analyzer ratio, limiting the upper
38 energy/charge range for a given high voltage capability.
39 Also a larger Δ_1 causes greater vulnerability to noise from
40 solar Ly-a UV radiation and the photo electrons that they
41 produce, penetrating to the detector by reflecting from ESA
42 electrodes which are more widely spaced apart.

43 The ESA design calls for only one insulating part, the
44 “inner support” that mounts other ESA parts and provides
45 high voltage (up to 5 kV) isolation between the inner and
46 center electrodes. Instead of PEEK, this part was
47 temporarily printed in another high-performance plastic
48 called PEI (Ultem) due to limited material availability for
49 some of the testing.

Table 1: ESA Design Parameters and predicted performance based on SIMION and C83.

Name	Comment	Value	Unit
R_1	Radius of inner electrode	1.72	cm
R_2	Radius of center electrode	1.86	cm
R_3	Radius of outer (top cap) electrode	2.00	cm
Δ_1	Gap between inner and center electrodes	0.138	cm
Δ_1/R_1	Controlling performance ratio	0.08	-
θ	Optimal $\frac{1}{2}$ -angle subtended by hole at pole of center electrode	17.5	deg
	(As built)	25	
σ	Optimal truncation angle of hemispheres near equatorial plane (From C83)	9	deg
	(As built)	3	
G	Predicted geometric factor (From C83)	0.0060	cm ² -sr-eV/eV
	Predicted geometric factor (From SIMION ray tracing)	0.0073	
$\Delta E/E$	Electron energy bandwidth FWHM (from SIMION)	21%	-
ΔAz	Polar angle bandwidth FWHM (from SIMION)	9.4	deg
A.R.	Analyzer Ratio (k-factor): Ratio of electron energy to ESA voltage. (theoretical)	6.25	-

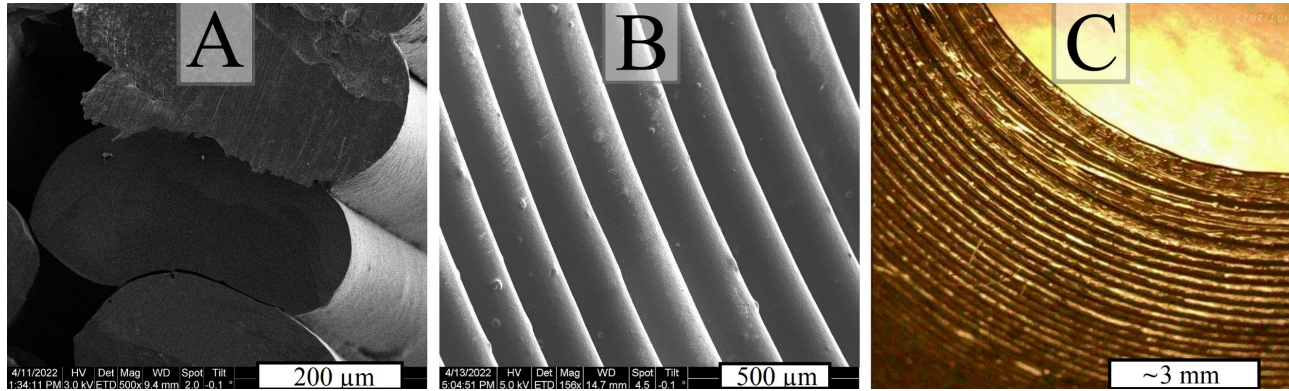


Figure 3: Views of the printed ESA. A and B are from a Scanning Electron Microscope. A shows a cut through several layers, showing where the extruded lines of plastic bond together. B shows the most overhanging part of the Center Electrode, where each bright line is the seam between plastic extrusions. C shows the same surface as B at larger scale, through an optical microscope.

3. ESA Fabrication

CNT-PEEK ESAs designed as described above have been fabricated at the University of Alaska Geophysical Institute using an Intamsys Funmat HT printer. This printer features exceptionally high temperatures on the nozzle, printing bed, and build chamber, necessary for high performance plastics like PEEK and PEI. Parts were printed with a nozzle temperature of around 420 °C, although the true temperature of the plastic is somewhat colder while it is being extruded. The build chamber was operated at 90 °C, and the printing bed at 140-160 °C. The high chamber and bed temperatures improve plastic adhesion and reduce warping or cracking of the print. Nano Polymer Adhesive from company Vision Miner was used to improve adhesion to the carbon fiber printing bed. Remaining adhesive on the parts was sanded away before vacuum testing to ensure it wouldn't alter the final material properties.

The layer-by-layer AM process presents difficulty in overhang areas where material must be extruded above empty space, especially when the overhang angle exceeds 60° from vertical. This ESA design contains severe overhangs on the inner and center electrodes, highlighted in Figure 2 as “Overhang Area”. Temporary supporting material was printed below such overhangs, to be removed in post-processing. Only a single-nozzle printer was available for this work, therefore, the support material had to be the same plastic as the main part. When properly printed, support material only lightly adheres to the main part, so we manually removed it with hand tools. To achieve consistent surface quality, we avoided using support material under the electrode surfaces which guide

electrons through the ESA. This posed a challenge for the center electrode, where there are overhangs at up to 65° from vertical near the entrance. For these unsupported but optically important overhanging areas, we tried numerous slicing software settings, and found success with the use of low nozzle movement speed, aggressive cooling, and unusually wide extrusions (~0.4 mm) at 0.15 mm layer thickness. Print time required for all parts of our ESA was under 8 hours. In the future we intend to use a multi-headed printer and soluble support material. Soluble support material will allow overhangs to be reliably printed with better surface quality. Figure 3 shows three microscope views of printed ESA parts. The naturally occurring ridges of the printed surface shown in Figure 3 are encountered by electrons and UV photons as they enter the ESA. We believe this surface has a serendipitous effect of acting like optical roughening or serrations to reduce UV and out-of-band electron transmission.

The ESAs tested in this document were not built to space-flight quality standards, and high-precision positioning or alignment of the parts during assembly was not a priority. Post-processing time for an ESA was only a few hours, including support material removal, hole drilling/tapping, cleaning, and hand-fitting the screw interfaces. Though it is feasible to post-process a printed part with machine tools if extremely accurate surfaces or holes are required, we did not do so. The printer was not operating at its limits of accuracy or surface finish for these ESA parts. To achieve better manufacturing accuracy and lower surface roughness at the expense of time, thinner layers with lower print speeds and more narrow extrusions can be used. The ultimate limits of additive manufacturing are still

1 unknown. While the basic process of plastic extrusion may
 2 never be as repeatable as metal milling, we predict that the
 3 overall electrode alignment might be more accurate with a
 4 “monolithic” printing technique. Compared to traditional
 5 methods, a monolithic ESA would avoid all assembly
 6 errors and error-prone mechanical interfaces, because it
 7 would be one fused-together piece of plastic, combining all
 8 the electrodes and insulators.

9 **4. Performance and Environmental Testing**

10 Testing was performed both at the University of Alaska
 11 Fairbanks (UAF), and at NASA’s Goddard Space Flight
 12 Center (GSFC). The GSFC facility has well-established
 13 history calibrating such space flight instruments; e.g., the
 14 Dual Electron Spectrometers of the FPI instruments
 15 (Pollock, et al., 2016) now flying on NASA’s MMS (Burch
 16 et al., 2016) mission. The test program is summarized in
 17 Table 2, where each test and its results are described below.

18 **Resistivity Analysis**

19 The first tests of printed CNT-PEEK were conductivity
 20 measurements using ordinary handheld multimeters and a
 21 high-voltage insulation testing multimeter. Resistances
 22 across the surface are difficult to measure accurately
 23 because the probe’s contact geometry with the surface has
 24 a dramatic influence on the readings. To avoid this
 25 uncertainty, we measured resistance between #0-80
 26 (~1.5mm) sized steel screws inserted in threaded holes on
 27 the outer rim of the ESA’s center electrode. Measured
 28 resistance values extended from less than 10 kΩ to 1 MΩ,
 29 depending on factors including part geometry, printing
 30 conditions, and screw tightness. We crudely estimate the
 31 volume resistivity is on the order of $10^4 \Omega \cdot \text{cm}$ or less.
 32 Charging time constant calculations and a practical
 33 demonstration to support the plastic’s viability are shown
 34 in the following section titled “ESA Voltage Sweeping”.

Table 2. Summary of testing and results.

Test	Location	Results	Conclusions
CNT-PEEK resistivity estimate	UAF	$10^4 - 10^6 \Omega$ measured between screws in the plastic, depending on several uncontrolled variables and print settings.	Nominally sufficient. Updated plastic formula and printing techniques may be needed to achieve lower resistivity.
ESA voltage sweeping	UAF	The printed ESA detects an electron beam at the same voltages during 100 Hz voltage sweeps as during steady-state operation	The ESA is conductive enough to behave electrostatically like a metal ESA at high voltage sweeping rates.
Energy-angle scans	GSFC	Plastic ESA yields a band pass similar to metal, with reduced out-of-band electron transmission.	Printed CNT-PEEK ESA electron optics work more ideally than metal ESA.
UV Transmission	GSFC	Printed CNT-PEEK ESA detects 100x less UV than aluminum.	Printed CNT-PEEK surface is roughly 10x less reflective than aluminum at 121nm. Surface blackening coatings may not be needed for certain designs.
UV Photoelectrons	GSFC	The printed CNT-PEEK shows higher-energy photoelectrons, implying its work function is significantly smaller than that of Aluminum.	This is unfortunate, but despite the lower work function, CNT-PEEK photoelectron counts are still much less than aluminum.
High-flux electron beam	UAF	ESA behaves almost identically when exposed at high and low beam fluxes at 2 keV.	The CNT-PEEK ESA can absorb significant plasma current onto its surfaces without influencing performance at 2 keV.
ESA temperature testing	UAF	ESA voltage bandpass remains consistent across temperatures, even at high beam flux.	The CNT-PEEK ESA will work well across the range of normal earth-orbiting thermal environments.
RG/Outgassing	GSFC	No signs of excessive outgassing or contamination.	This printed PEEK probably does not pose a molecular contamination threat to MCPs
Vibration	UAF	No damage after 20-G GEVS profile for 20 minutes in each of two orientations	A printed PEEK ESA will survive rocket launches.

1 In an extreme environmental charging case of only
 2 electrons impacting the ESA's top cap with number density
 3 of 40 cm^{-3} and speed of 1000 km s^{-1} (flux = 4×10^9 electrons
 4 $\text{cm}^{-2}\text{-s}^{-1}$) with a top cap resistance of $1 \text{ M}\Omega$, the top cap
 5 would still only be expected to charge at 0.03 V relative to
 6 spacecraft ground. Such a voltage error would likely only
 7 harm the ESA's performance at energies below about 1 eV .
 8 While this appears to be a worst-case analysis, we are
 9 assuming a homogenous conductivity, which may be

27 Electron Energy-Angle Scans

28 A spatially broad ($\sim 8 \text{ cm}$ wide) electron beam was directed
 29 toward the ESA. The beam energy was 3 keV and
 30 Helmholtz coils were in use cancelling about 90% of the
 31 Earth's magnetic field, so any magnetic curvature of the
 32 beam was negligible. Transmitted electrons impacted an
 33 MCP detector whose output pulses were counted, so that
 34 each voltage-azimuth angle combination has an associated

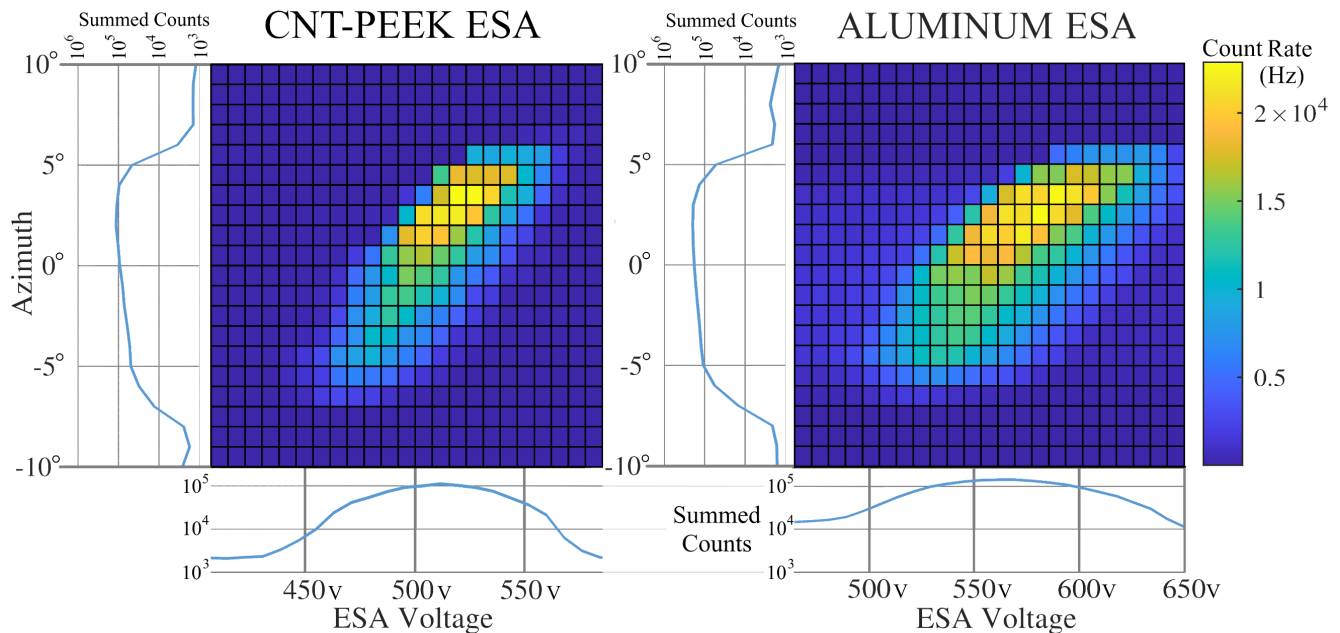


Figure 4. Energy-Angle Scans for CNT-PEEK and Aluminum ESAs, with 1-D angle and voltage distributions obtained by summing over the neglected dimension in each case. Response of ESAs made from CNT-PEEK (left) and Aluminum (right) are compared. The voltages are not the same.

10 unrealistic for this case of carbon nanotubes embedded in
 11 an insulating material.

12 We investigated conductivity variation over temperature
 13 by placing a printed CNT-PEEK inner electrode in a
 14 laboratory freezer. Resistance measured screws on the
 15 center electrode was $40 \text{ k}\Omega$ at $+20^\circ \text{ C}$ and $100 \text{ k}\Omega$ at -80° C .
 16 Clearly temperature does influence the conductivity
 17 significantly, in a similar pattern as a semiconductor, but
 18 the increased resistance is likely still acceptable. While the
 19 bulk conductivity is sufficient, surface conductivity on a
 20 microscopic scale is not fully resolved. A critical question
 21 remains as to whether microscopic insulating islands might
 22 appear on the material surface, especially at cold
 23 temperatures, causing localized surface charging sufficient
 24 to interfere with of transmission of low energy ($< 100 \text{ eV}$),
 25 as has been hypothesized in (Fedorov et al., 2011). This is
 26 further discussed in Chapter 5.

35 count rate measurement. This test was performed in the
 36 GSFC chamber on an automatic motion control stage
 37 which swept the azimuth angle from -10 to $+10^\circ$ in 1° steps.
 38 At each angle step, the ESA voltage was stepped in $\sim 10 \text{ V}$
 39 increments over the full ESA voltage band pass. Variations
 40 of beam flux throughout the experiment were measured
 41 with a Faraday Cup but found to be negligible. The results
 42 shown in Figure 4 correspond to a single polar angle,
 43 equidistant between two of the ESA's top cap supports.
 44 The data show that the overall energy-angle bandpass
 45 shape is very similar for the CNT-PEEK and metal ESAs,
 46 as expected. The band passes are centered at slightly
 47 different voltages, probably owing to manufacturing and
 48 assembly differences between the metal and CNT-PEEK
 49 ESAs. Evidently the metal ESA has a somewhat wider gap
 50 between the electrodes, causing higher voltages to be
 51 required to transmit the 3 keV electrons. The CNT-PEEK
 52 ESA's energy bandpass is more narrowly confined,

1 compared to that of the Aluminum ESA. This more severe
 2 out-of-band electron transmission is almost certainly
 3 caused by electrons that have collided with one of the ESA
 4 electrodes but were still scattered forward, eventually
 5 reaching the detector when they should have been
 6 absorbed. We expect that the CNT-PEEK has a reduced
 7 secondary electron yield compared to metal, because it is a
 8 rougher surface, and because it is primarily composed of
 9 lighter atoms (carbon and hydrogen), as opposed to a metal
 10 like aluminum. Accurately inspecting the dimensions and
 11 surface properties of the ESAs was not within the scope of
 12 this work, and therefore it is difficult to quantitatively
 13 compare properties based on Figure 4's results. After
 14 normalizing for the different beam currents, the metal ESA
 15 had 1.46x higher total counts across the entire energy-angle
 16 scan but the analyzer ratio was 9% smaller. These are likely
 17 related, indicating that the metal ESA probably had a larger
 18 gap between the electrodes. According to (Carlson 1983)'s
 19 Fig.6, we expect a 9% smaller analyzer ratio to correspond
 20 with a 25-30% increase in sensitivity (geometric factor).
 21 However, we are not able to conclude whether all the
 22 differences are due to manufacturing and assembly, or due
 23 to surface roughness, or potentially due to a fundamental
 24 difference between the materials. The roughly 0.1mm-
 25 sized ridges which form due to the printing layers may alter
 26 the PEEK ESA's electron optics.

27 Figure 5 shows a comparison between the CNT-PEEK and
 28 Aluminum ESA E/q band passes after summing across
 29 azimuth angle and placing them on common and
 30 independently normalized energy and count rate scales.
 31 This graph is created from the same GSFC data as is shown
 32 on the bottom of Figure 4. The CNT-PEEK and Aluminum

33 band passes are similarly shaped, falling off more steeply
 34 at low voltages than at higher voltages. There are, however,
 35 significant differences between the two materials. The
 36 Aluminum ESA response has a broader peak and exhibits
 37 out-of-band response at nearly 10% of the peak count rate,
 38 even when at only 75% of the peak voltage. The CNT-
 39 PEEK ESA has a narrower bandpass and exhibits out-of-
 40 band response of under 1% of the peak count rate, which is
 41 near the detector background noise level. The signal-to-
 42 noise ratio for these measurements was limited to only
 43 about 200 because of MCP dark counts. The increased out-
 44 of-band response of the Aluminum ESA is undesirable
 45 because it represents a reduction in energy resolution, and
 46 a source of electron energy ambiguity. An ideal ESA would
 47 absorb those out-of-band electrons such that none reach the
 48 detector. This result implies that the CNT-PEEK surfaces
 49 have the desirable effect of reduced forward scattering of
 50 electrons, and perhaps also reduced forward emission of
 51 secondary electrons. This is probably caused by the surface
 52 roughness from 3D printing layers, but might also be
 53 caused by an intrinsically low secondary electron yield.
 54 However, the aluminum ESA was not coated in this
 55 comparison.

56 ESA Voltage Sweeping

57 For many space-flight plasma applications which demand
 58 precise time and position resolution of electron energy
 59 spectrum measurements, the ESA must rapidly sweep
 60 through a wide range of voltages. Voltage sweeping is
 61 necessary to provide electron spectra covering several
 62 energy decades many times per second. We tested the
 63 CNT-PEEK ESA with a 3-decade exponentially decaying
 64 voltage sweep at 8 ms cadence (sweep time

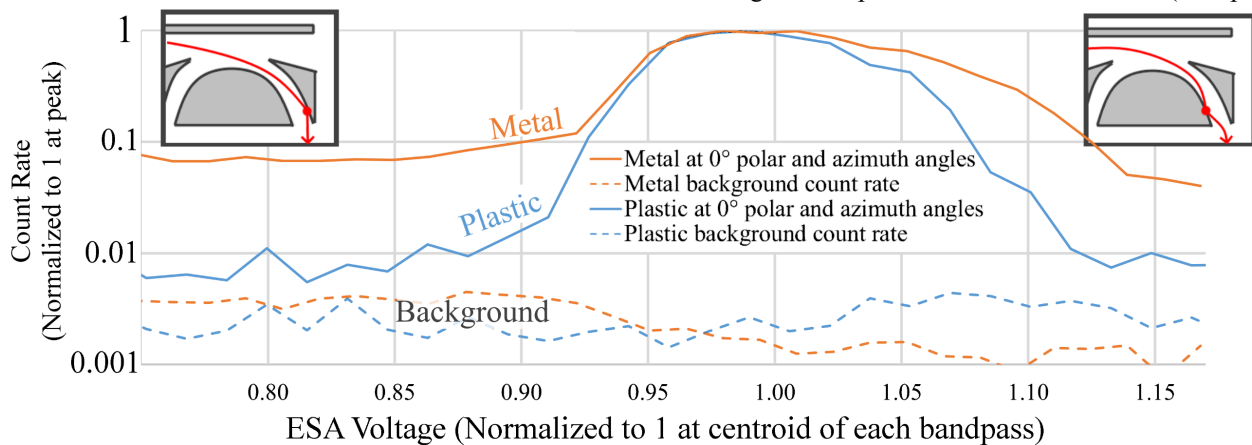


Figure 5: Out of band electron comparison from the GSFC Energy-Angle Scans. The vertical axis is log-scaled to show the "tail" off both sides from the peak ESA count rates.

1 constant ≈ 1 ms). The voltage re-trace time at the end of
 2 each sweep was approximately 1 ms, and the sweep
 3 repetition rate was 100 Hz. For the somewhat resistive ESA
 4 electrodes to effectively follow the power supply's driving
 5 voltage, their R*C time constant must be short compared
 6 to the power supply voltage variations. This should be
 7 achievable with the CNT-PEEK ESA given its <1 M Ω
 8 resistance and ~ 10 pF capacitance that yield a time constant
 9 on the order of 10 μ s. Therefore, the ~ 1 ms voltage retrace
 10 time is long enough for 100 ESA R*C time constants to
 11 occur, ensuring that the ESA voltage is not significantly
 12 "lagging behind" its power supply.

13 Tests of ESA electron transmission at UAF used a Faraday
 14 cup directly under the ESA instead of an MCP detector,
 15 because we did not have a MCP detector at UAF. Negative
 16 Faraday cup signal seen in Figure 6 represents transmission
 17 of electrons through the ESA. The Faraday cup we used has
 18 no electron multiplication, so it required a much more
 19 intense electron input to produce a measurable output than
 20 an MCP detector. Therefore, the UAF tests used fluxes of
 21 10^{10} - 10^{12} electrons-cm $^{-2}$ -s $^{-1}$, while the GSFC tests used
 22 only 10^5 - 10^6 electrons-cm $^{-2}$ -s $^{-1}$. Tests at UAF also used a
 23 2 keV electron beam, while those at GSFC used 3 keV.
 24 Figure 6 shows the Faraday cup current signal responding
 25 as the ESA voltage sweeps through a certain ESA voltage

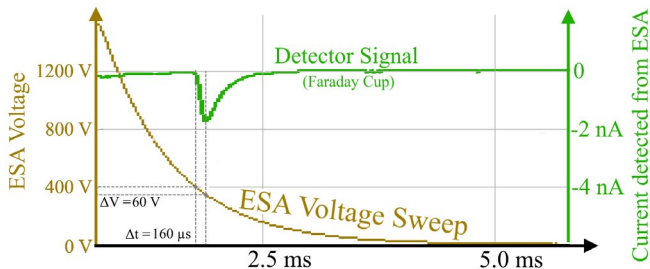


Figure 6: Fast CNT-PEEK ESA voltage sweep (tan, scale on left) and Faraday Cup detector response (green) in the presence of a 2 keV electron beam.

26 bandpass. The Faraday cup was placed directly below the
 27 ESA's exit aperture, so it was measuring only the electrons
 28 which the ESA allowed through.

29 The electron beam energy was maintained at 2 keV, and
 30 the Faraday cup collected measurable current only when
 31 the ESA voltage swept through the ESA's E/q bandpass.
 32 The Faraday cup is seen to have collected significant signal
 33 when the ESA was between 410 V and 350 V, matching
 34 closely with range of constant (non-sweeping) voltages
 35 where this ESA detects a 2 keV beam as seen in Figure 7
 36 below. This similarity in performance between steady-state
 37 and fast sweeping demonstrates that the CNT-PEEK ESA

38 can be used to acquire electron energy spectra at high
 39 voltage sweeping rates, and therefore at fine time
 40 resolution on the order of 100 Hz or more. The exponential
 41 decay seen after the detector signal peak in Figure 6 is
 42 dominated by the faraday cup circuitry not the ESA. The
 43 faraday cup preamplifier intentionally had a high R*C so it
 44 was acting as an integrator.

45 High-Flux Beam Testing

46 Accumulation of charge from the space environment onto
 47 insufficiently conducting surfaces of an ESA-based plasma
 48 instrument can disrupt the measurements. High-flux testing
 49 was performed at the UAF Space Systems Engineering
 50 Laboratory in a thermal vacuum chamber to test for surface
 51 charging effects under high beam flux conditions and
 52 extreme temperatures. Results of high-flux testing at room
 53 temperature are shown in Figure 7. Even the lowest beam
 54 flux among the three fluxes tested is several times more
 55 intense than that of an extreme hypothetical situation of a
 56 solar wind consisting of only electrons with number
 57 density of 40 cm $^{-3}$ and bulk speed of 1000 km-s $^{-1}$, carrying
 58 an electron flux of 4×10^9 cm $^{-2}$ -s $^{-1}$. A complete analysis of
 59 the worst-case charging conditions has not been done.
 60 Some locations such as the magnetosheath may have more
 61 intense fluxes. This requires additional analysis of
 62 electrons and ions across all energies, plus photoelectrons
 63 caused by solar radiation of all energies

64 Only a 3 V ($\sim 1\%$) shift in the bandpass centroid was seen
 65 when comparing the high flux and low flux measurements.
 66 Consistent performance at various intense beam fluxes
 67 indicates that the CNT-PEEK is sufficiently conductive to
 68 dissipate charge collected from the local environment at
 69 room temperature, at least for use with higher energy
 70 electrons. All UAF beam tests were performed with 2 keV
 71 electrons in a Helmholtz cage. However, we still

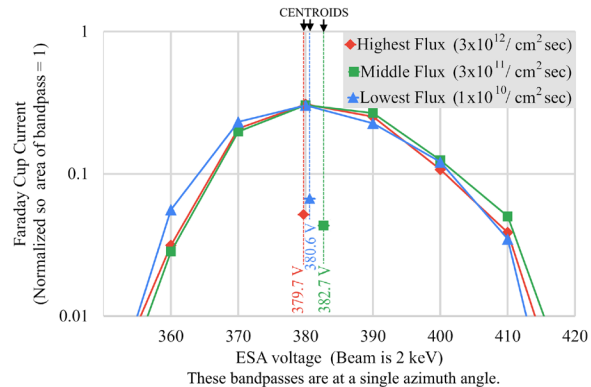


Figure 7: Printed ESA voltage band passes at various beam fluxes

1 encountered excessive magnetic deflection below 500 eV
 2 and were unable to collect consistent measurements,
 3 because the chamber and stepper motors were still
 4 dramatically altering the magnetic environment. To fully
 5 address surface charging concerns at lower electron
 6 energies, tests with better magnetic cancellation are
 7 necessary. Alternatively, tests with a beam of much more
 8 massive ions instead of electrons will allow dramatically
 9 reduced magnetic disturbance errors, simply requiring the
 10 ESA and electron gun voltage polarities to be reversed.
 11 **Beam Testing over Temperature**

12 The CNT-PEEK ESA performance was tested over
 13 temperature in thermal vacuum chamber. The chamber
 14 used a heat exchanger plate to heat or cool the ESA and its
 15 mounting fixture. To improve the chamber's ability to cool
 16 the ESA, it was surrounded by a sheet aluminum shroud to
 17 reduce radiative heating from the chamber walls.
 18 Temperature of the ESA was measured using a
 19 thermocouple attached near the mounting screws of the
 20 ESA. Figure 8 shows the results of three tests at hot,

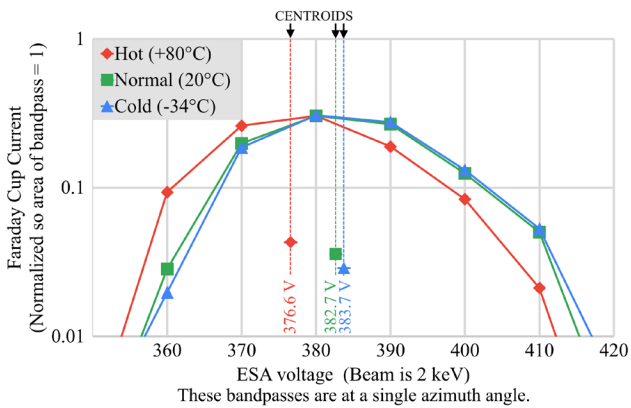


Figure 8: Printed ESA voltage bandpass at various temperatures

21 normal, and cold temperatures, which were all conducted
 22 at beam fluxes within $\pm 50\%$ of $3 \times 10^{11} \text{ cm}^{-2}\text{-sec}^{-1}$. A small
 23 shift (approximately 6 Volts or 1.5%) of the ESA voltage
 24 bandpass was seen at $+80^\circ \text{C}$ (red line). While it is possible
 25 that an electrical change in performance occurred, this
 26 band pass shift may have also been caused by thermal
 27 expansion or warping of the ESA and/or its mounting
 28 fixture. Plain PEEK's coefficient of thermal expansion of
 29 $\sim 45 \text{ ppm/K}$ is roughly twice that of aluminum, although we
 30 don't have data for this specific CNT-PEEK.

31 **UV Photons**

32 Ultra-violet (UV) photon testing was performed to
 33 determine how effectively the ESA suppresses photon

34 transmission to the detector. This is important because far-
 35 ultraviolet photons produced by the Sun (primarily Lyman-
 36 α at 121 nm) can trigger an MCP detector and represent an
 37 important or even debilitating noise source. UV Photon
 38 testing was performed in the same GSFC testing chamber
 39 as were the energy-angle scans shown in Figures 4 and 5.
 40 The Krypton gas UV source produces two emission lines
 41 very close to 121 nm. Based on prior calibrations with a
 42 photodiode, the UV flux was estimated to be $6 \pm 2 \times 10^{11}$
 43 photons- $\text{cm}^{-2}\text{-sec}^{-1}$, slightly greater than the solar Lyman- α
 44 flux near Earth. This photon testing was intended only to

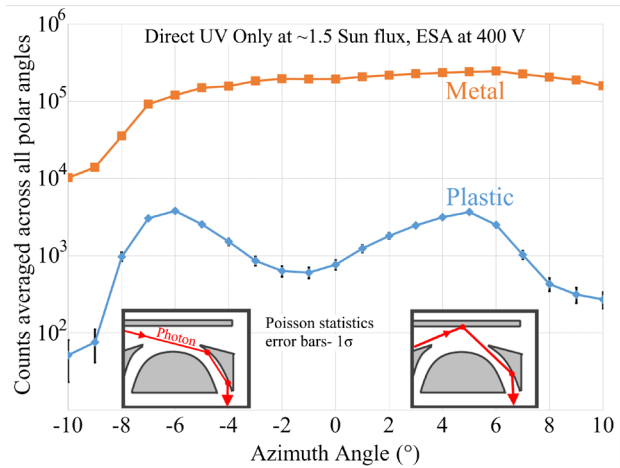


Figure 9: Comparison of count rates vs. azimuth angle for ESAs made from CNT-PEEK (blue) and Aluminum (orange) under laboratory-simulated solar Ly- α illumination. The insets illustrate hypothesized 2-bounce paths producing the two peaks in the CNT-PEEK ESA response.

45 measure the direct transmission of scattered photons, but
 46 not photoelectrons. To ensure photoelectrons were
 47 rejected, we operated the ESA at $+400 \text{ V}$, sufficient to
 48 attract any photoelectrons on to the inner electrode and
 49 prevent them from reaching the detector. Any
 50 photoelectrons must have relatively low energies of less
 51 than 11 eV, the value of a 121 nm UV photon's energy.

52 Figure 9 shows the UV-induced count rate plotted versus
 53 incident azimuth angle (see Figure 1) for the CNT-PEEK
 54 ESA (blue line) and the aluminum ESA (orange line). The
 55 aluminum ESA shows a relatively large and uniform UV
 56 contamination across polar angles. In contrast, the CNT-
 57 PEEK ESA shows substantially reduced response and is
 58 non-uniform, displaying two distinct peaks, near -6° and
 59 $+5^\circ$ polar angles.

60 Based on results of a simple MATLAB ray tracing script,
 61 we believe the main source of UV counts and the two-peak

1 structure in the CNT-PEEK ESA response is due to two
 2 families of two-bounce paths available for photons to reach
 3 the detector through the ESA, sketched as insets in Figure
 4 9. One family of paths, near $+5^\circ$, includes reflections first
 5 from the top cap and then from the center electrode. The
 6 second family, near -6° , includes two reflections, both from
 7 the center electrode. It is possible to eliminate these two-
 8 bounce paths by extending the inner and center electrodes
 9 slightly beyond the ESA equatorial plane. A trade is
 10 required however, because this truncation angle (σ in
 11 Figure 2) controls the quality of focus for incoming parallel
 12 trajectories at the detector. We wish to extend the
 13 electrodes sufficiently to eliminate the 2-bounce photon
 14 paths while not unduly degrading the ESA's polar angle
 15 resolution. A potentially similar situation of UV
 16 suppression and carbon-based material was on the MIMA
 17 instrument (McCann et al, 2007). They used machined
 18 graphite for portions of the instrument to suppress UV and
 19 secondary electrons. They also used a "photon trap" near
 20 the ESA entrance made of thin metal plates parallel to the
 21 incoming photon paths. We plan to combine those ideas
 22 and 3D print complex light-trapping structures with a
 23 naturally UV-absorptive plastic.

24 When integrated over the 2D angular field of view, our UV
 25 measurements show that this CNT-PEEK ESA rejects UV
 26 photons $\sim 100x$ more effectively than the uncoated
 27 Aluminum ESA we tested. However, aluminum ESAs for
 28 space flight are typically fabricated with serrations
 29 machined into their electrode surfaces and have those
 30 surfaces coated with materials such as Copper Sulfide
 31 Black (Cu_2S) or Gold Black to reduce UV transmission.
 32 The superior inherent rejection of the CNT-PEEK ESA
 33 may, with optimizations like described above, be sufficient
 34 to allow its effective use without resorting to the
 35 application of black absorptive coatings on the ESA
 36 electrodes, a costly and delicate process in the flight
 37 instrument development cycle.

38 The UV photon rejection is likely due to a combination of
 39 material properties and the surface texture. The 3D printed
 40 surface naturally has ridges between printing layers which
 41 likely trap photons that reflect at shallow angles. Similarly-
 42 shaped serrations are intentionally machined into many
 43 metal ESAs for UV rejection. Although we did not directly
 44 measure the CNT-PEEK's single-bounce UV absorption, it
 45 can reasonably be expected to be much higher than metals.
 46 Hydrocarbon polymers are generally known for absorbing
 47 UV and PEEK is no exception. Absorptivity in the range
 48 of 90% was seen with a PEEK film by (A. Jolly, 2019).

49 Carbon nanotubes are also effective at absorbing many
 50 wavelengths of light. The famous coating
 51 "VANTABLACK" achieves exceptional absorptivity from
 52 carbon nanotubes. We expect that further increasing the
 53 concentration of nanotubes will yield an even higher UV
 54 absorptivity beyond that of plain PEEK.

55 Photoelectrons

56 This test is similar to the UV direct transmission test
 57 described above, except that the ESA is operated over the
 58 range 0 to +5 volts, instead of fixed at +400 V, in order to
 59 perform electrostatic analysis of any emitted
 60 photoelectrons. The background level of direct UV was
 61 assumed to be at an ESA voltage of 10 V, because 10 V
 62 should be enough to attract and absorb the vast majority of
 63 121 nm photoelectrons before they reach the detector.
 64 Figure 10 shows the count rates with the $10 V_{ESA}$ baseline
 65 level subtracted. Figure 10 demonstrates that the CNT-
 66 PEEK and aluminum ESAs both exhibit count rate peaks
 67 at a certain low ESA voltage, indicating the presence of
 68 significant photoelectrons. However, the peaks are found
 69 at different voltages. The CNT-PEEK photoelectrons peak
 70 near $1.5 V_{ESA}$, while those from the aluminum ESA peak
 71 near $0.5 V_{ESA}$. This may imply that the photoelectrons
 72 emitted from the CNT-PEEK were considerably more
 73 energetic than those emitted from the aluminum and, by
 74 extension, that the CNT-PEEK has a lower work function
 75 than that of the aluminum. However, this implication is
 76 questionable because we don't know where in the ESA
 77 these photoelectrons were emitted and therefore the extent
 78 of electrostatic filtering to which they were subjected.
 79 While a lower work function may turn out to be a
 80 disadvantage of CNT-PEEK, the total photoelectron count
 81 rate was still 53x smaller in the CNT-PEEK ESA than the
 82 aluminum ESA, and noise from photoelectrons represents

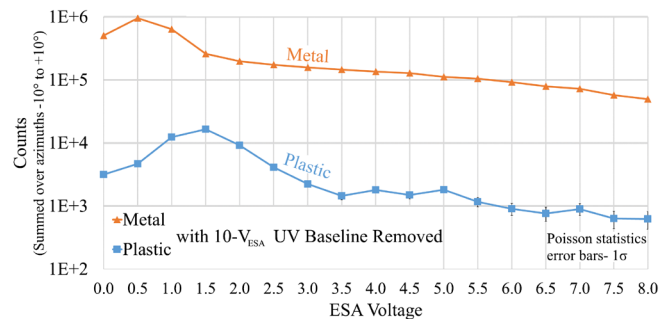


Figure 10: UV Photoelectrons comparing CNT-PEEK and Aluminum ESAs. Data is integrated across azimuth angles over the range $(-10^\circ, 10^\circ)$.

1 a small contribution, localized near a few eV, compared to
 2 the potentially much larger signal from direct photons that
 3 extends uniformly across the entire ESA energy range. For
 4 both materials, these peaks which we attribute to
 5 photoelectrons were 20-30% higher than the 10 V_{ESA}
 6 background count rate. Note that all UV and photoelectron
 7 testing includes the uncertain variable of the MCP's
 8 detection efficiency for UV, which is likely in the range of
 9 1-10% but varies based on MCP manufacturing techniques.

10 **Vibration Testing**

11 The printed CNT-PEEK ESA was subjected to random
 12 vibration testing in two orientations, as is typical in
 13 qualification testing for space flight. We scaled the NASA
 14 GEVS (General Environmental Verification Standard)
 15 14.1g qualification test profile up to 20 G RMS to make a
 16 more challenging test. Figure 11 shows a photo of the ESA
 17 in “flat” orientation on the vibration table at UAF’s College
 18 of Engineering and Mines. The ESA was also tested in the
 19 shearing orientation, such that vibratory acceleration was
 20 applied in the direction transverse to the ESA symmetry

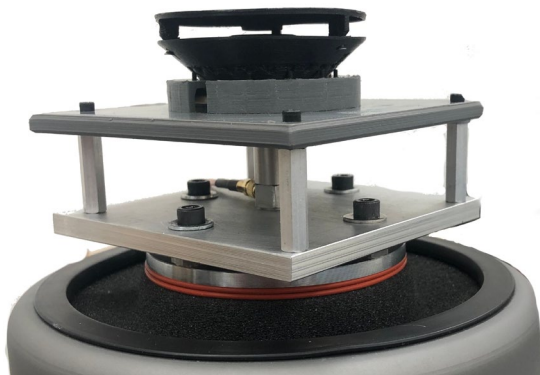


Figure 11: Printed ESA on vibration table.

21 axis, applying shear forces to the relatively narrow posts
 22 that support the top cap.

23 Figure 12 shows the vibration frequency spectrum which
 24 was applied to the ESA. There was no damage to the ESA
 25 after 20 minutes in both orientations at 20 G RMS. The
 26 ESA did show a distinct resonance in the “flat” orientation
 27 at about 440 Hz. We assume the top cap is the most likely
 28 source of this resonance by moving like a drum head, since
 29 it is only supported at three points along its outer edge.

30 Finally, we added 30 grams (nearly 3x the CNT-PEEK
 31 ESA’s own mass) of aluminum screwed on to the top cap,
 32 to simulate electronics being mounted in that location. The
 33 ESA survived a 20-minute vibration with that additional
 34 mass in the shearing orientation at 14.1G RMS.

36 **Outgassing and Residual Gas Analysis**

37 We were initially concerned that voids between the printed
 38 extrusion lines of plastic may cause increased outgassing
 39 or “virtual leaks” in vacuum. In practice, this has not been
 40 a problem. We have not noticed any troublesome increase
 41 in vacuum pumping time required to reach a certain
 42 pressure. The increased surface area on printed parts
 43 probably does retain some additional adsorbed water and
 44 air, but it has not been an obstacle to reaching the pressures
 45 we expect to achieve. Baking at about 100°C has allowed
 46 these printed parts to reach the limits of UAF’s vacuum
 47 chambers, roughly 5×10^{-8} torr, and we did not encounter
 48 trouble reaching pressures around 1×10^{-7} torr on GSFC’s
 49 cryo-pumped chamber either.

50 The results from Residual Gas Analyzer testing at GSFC in
 51 Figure 13 show no significant difference between the
 52 empty chamber test case (black) and the test with the CNT-
 53 PEEK ESA inside (orange). This indicates that outgassing
 54 from the CNT-PEEK is probably not a concern. Most

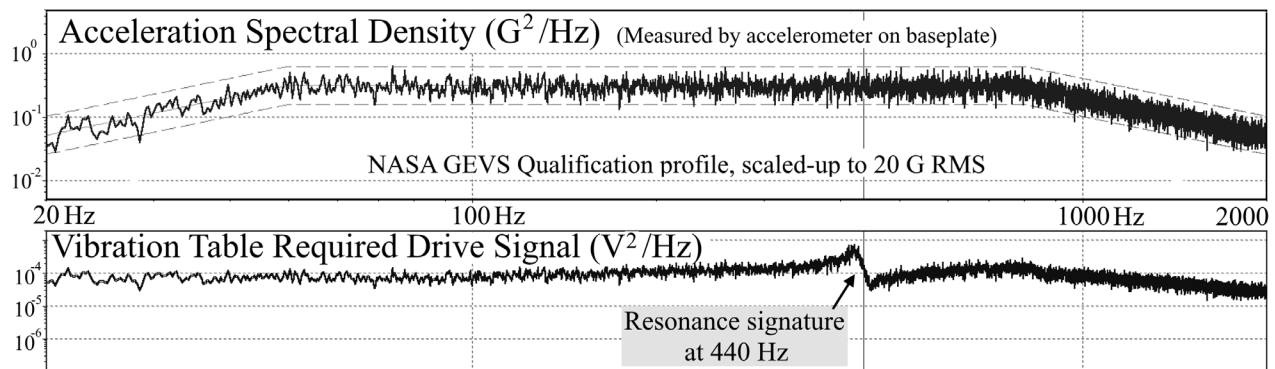


Figure 12: Resonance seen at ~440 Hz on the vibration table input drive signal from 20g-intensified GEVS vibration

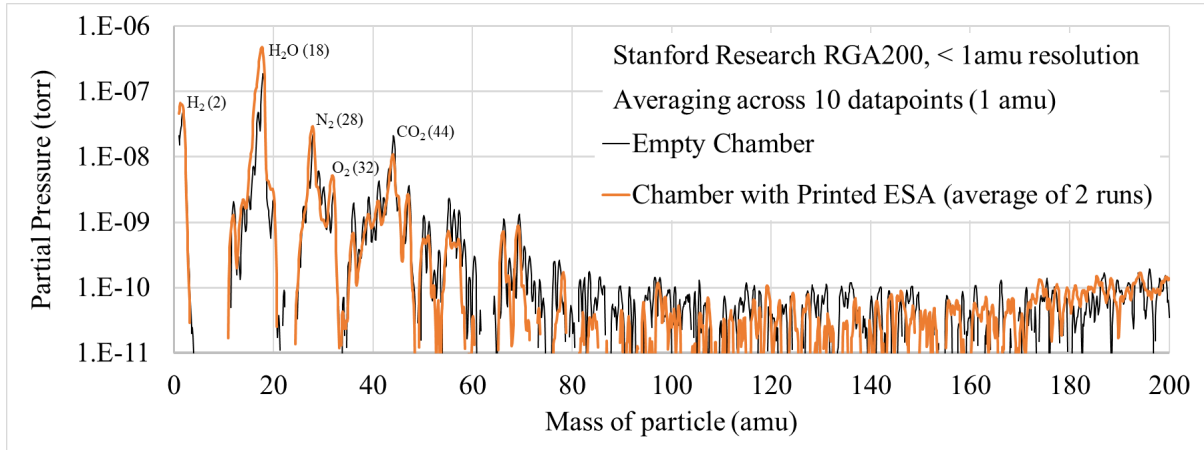


Figure 13: Comparing RGA scans of empty chamber and printed ESA

1 importantly, the measurements at the highest molecule
 2 masses are very near the RGA’s noise floor, indicating that
 3 there are very few high-mass hydrocarbons, which are the
 4 largest threat for condensing and degrading MCPs or other
 5 sensitive surfaces. The main pressure peaks all correspond
 6 to easily identifiable low-mass gases which probably will
 7 appear in any normal RGA scan. A full outgassing analysis
 8 of condensable material should be done in the future.

9 5. Conclusions and future directions

10 The use of CNT-filled PEEK in an AM fabrication of a
 11 realistic ESA design for scientific space flight is
 12 demonstrated to be feasible, although some concerns
 13 remain. At least for the keV electron energies we tested,
 14 the as-built CNT-PEEK ESA clearly has sufficient
 15 electrical conductivity to execute exponential voltage
 16 sweeps as needed for high resolutions science
 17 measurements. Very fast stepped voltage sweeping may
 18 still be limited, but we expect additional improvements in
 19 conductivity to make the plastic’s ESA’s R*C time
 20 constant even faster. Electron beam testing confirms that
 21 the CNT-PEEK printed ESA displays nominal energy and
 22 angle band pass performance, even at extremely high
 23 incident electron fluxes and extreme temperatures.
 24 Electron beam tests demonstrate that the CNT-PEEK ESA
 25 displays rejection of out-of-band electrons that is far
 26 superior to that of uncoated machined aluminum. Further,
 27 vacuum testing at GSFC under exposure to a beam of ~120
 28 nm UV photons simulating solar Ly- α intensity at Earth’s
 29 distance from the sun demonstrates that the CNT-PEEK
 30 ESA is also far superior to the uncoated machined
 31 aluminum in rejection of both directly reflected Ly- α
 32 photons and the photo-electrons that they generate within
 33 the ESA. We have tested the CNT-PEEK ESA’s electron

34 transmission properties over wide ranges of electron beam
 35 flux and ambient temperature, finding small variations in
 36 performance. We have shown that the CNT-PEEK ESA
 37 withstands vibration loads exceeding those expected to be
 38 encountered during a space launch, namely the GEVS
 39 standard. Finally, this work demonstrates that properly
 40 cleaned CNT-PEEK printed parts do not emit easily
 41 detectable amounts of heavy molecules under high
 42 vacuum, evidence that they may be suitable for use in space
 43 flight near contamination-sensitive surfaces.

44 There are several areas of remaining concern, yet to be
 45 fully resolved. These include possible electrical surface
 46 charging, degradation of the PEEK under long-term space
 47 exposure, and the on-orbit thermal performance of the
 48 CNT-PEEK.

49 There exists a previous space-borne ESA experiment that
 50 requires consideration. That is the Solar Wind Electron
 51 Analyzer (SWEA; Sauvaud et al., 2008) that was flown as
 52 part of the In situ Measurements of Particles and CME
 53 Transients (IMPACT; Luhmann et al., 2008) experiment
 54 on the two Solar Terrestrial Relations Observatory
 55 (STEREO; Kaiser et al., 2008) spacecraft. The SWEA
 56 instrument featured a top hat ESA, whose top cap electrode
 57 was coated with a Carbon-filled Teflon material called
 58 Nuflon™. Fedorov et al. (2011) described that, once on
 59 orbit, SWEA experienced anomalous transmission
 60 characteristics, such that solar wind electrons below about
 61 100 eV were not transmitted to the detector as expected.
 62 After extensive analysis, the authors concluded that the
 63 Nuflon surface had developed “isolated spatial domains”
 64 that lack sufficient conductivity to carry away incident
 65 electrons. They concluded that, taken together, these
 66 domains charged the top cap to an average of

1 approximately 4 V negative, and that this potential was
2 prohibiting normal transmission of solar wind electrons, as
3 observed. It is notable that the authors further concluded
4 that this phenomenon was induced by fracturing of chains
5 of carbon grains embedded in the Teflon surface in the
6 extremely cold conditions under which SWEA operates,
7 always in the shadow of the STEREO spacecraft, absent
8 the photon flux that could have neutralized acquired
9 negative charge by photo-emission. In the context of the
10 present paper this result introduces a future necessity for
11 low energy charged particle testing under cold conditions.
12 We have only just begun addressing this charging concern
13 with testing. At GSFC we informally did a single energy-
14 angle scan with a 50eV beam. That test inspired confidence
15 because it produced a nominal bandpass with only slight
16 distortion compared to the 3 keV bandpasses. However,
17 follow-up tests at UAF have yielded inconsistent results,
18 potentially due to inadequate equipment, or potentially
19 indicating a real charging problem. The much higher beam
20 flux at UAF vs GSFC may be the source of this difference.
21 If charging truly is a problem, it may be necessary to
22 reconsider the conductive plastic formula.

23 Thermal analysis indicates that the dark colored CNT-
24 PEEK will become hot under solar illumination in the
25 space environment, likely reaching surface temperatures
26 around 100 °C. Because of PEEK's low conductivity, it
27 will not reliably reach thermal equilibrium with the rest of
28 the spacecraft. This is not expected to be a problem,
29 because PEEK can survive and maintain dimensional
30 stability in temperatures well beyond 100 °C. However,
31 thermal expansion and warping are residual concerns, as is
32 the question of heat transfer from the hot ESA to sensitive
33 electrical components near it, such as the MCP detector and
34 the High Voltage Power Supply. It may be preferable to
35 thermally insulate electronics to protect them from ESA
36 heating.

37 AM-fabricated engineering plastics can provide several
38 important advantages for space-borne ESA experiments.
39 One of these, mass savings, is realizable in two ways. First,
40 the mass density of the CNT-PEEK (1.2 g/cm³) is less than
41 half that of Aluminum (2.7 g/cm³). Second, the AM
42 fabrication technique allows placement of material only
43 where it is needed for functional and structural
44 performance, so that unnecessary material can be more
45 readily omitted than in the case of conventional machining.
46 In addition, AM fabrication has the potential to enable
47 electron-optical geometric configurations, some as-yet

48 unimagined, that would be difficult or impossible to
49 implement using conventional machining techniques.
50 Finally, additive manufacturing of conductive plastics has
51 the potential to greatly simplify the process of flight
52 development for ESAs or other plasma instruments. This is
53 particularly important in consideration of deploying tens or
54 even hundreds of instruments in a space-flight
55 constellation scenario. The superior rejection of out-of-
56 band electrons, photoelectrons, and directly reflected solar
57 photons by the CNT-PEEK as compared to bare aluminum
58 holds the potential to eliminate the need for application of
59 black absorptive surface coatings on the ESA electrode
60 surfaces. Those coatings are notorious for causing
61 significant complexity in the processing and handling of
62 ESAs during the flight development phase. The use of
63 printers with multiple nozzles that feed different materials
64 admits the prospect of printing monolithic ESAs that are
65 almost immediately ready for flight, without alignment and
66 assembly struggles. Such simplifications in the flight
67 hardware development process are essential to enabling
68 constellation-type missions such as Magnetospheric
69 Constellation (MagCon; 36 spacecraft) and
70 Magnetospheric Constellation and Tomography (MagCat;
71 20 spacecraft) envisioned in the most recent US National
72 Academy of Sciences Heliophysics Decadal Survey
73 (2013).

74 A separate but related project at UAF is currently testing
75 whether MCPs are degraded by operating in close
76 proximity to printed PEEK. This experiment should be
77 completed by the end of 2024, and the results will inform
78 future designs involving printed plastic MCP detector
79 assemblies.

80 Degradation from exposure to the space environment is a
81 concern for the future. We don't expect a problem on
82 sounding rockets or low-orbiting CubeSats, but perhaps on
83 longer missions. Penetrating ionizing radiation, atomic
84 oxygen, or solar UV might degrade the PEEK. The main
85 concerns would be loss of surface conductivity or loss of
86 UV absorptivity.

87 Future development focuses on 1) retiring the concerns
88 described above with additional testing, 2) further
89 improving the UV rejection of the CNT-PEEK ESA, and
90 3) designing, manufacturing, and testing a fully monolithic
91 CNT-PEEK ESA. We hope to develop a complete
92 instrument based on our CNT-PEEK ESA and seek a test
93 flight on a sub-orbital rocket or an orbiting CubeSat.

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